



PRELIMINARY

SOLID STATE DEVICES, INC.

14005 Stage Road * Santa Fe Springs, Ca 90670
Phone: (562) 404-4474 * Fax: (562) 404-1773

SFF75N06-28

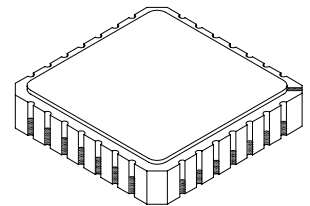
30 AMP ^{1/}
60 VOLTS
25mΩ
N-CHANNEL
POWER MOSFET

DESIGNER'S DATA SHEET

FEATURES:

- Rugged construction with poly silicon gate
- Low RDS (on) and high transconductance
- Excellent high temperature stability
- Very fast switching speed
- Fast recovery and superior dv/dt performance
- Increased reverse energy capability
- Low input transfer capacitance for easy paralleling
- Hermetically sealed surface mount package
- TX, TXV and Space Level screening available

28 PIN CLCC



MAXIMUM RATINGS

CHARACTERISTIC	SYMBOL	VALUE	UNIT
Drain to Source Voltage	V _{DS}	100	Volts
Drain to Gate Voltage (RGS = 1.0 mΩ)	V _{DG}	60	Volts
Gate to Source Voltage	V _{GS}	±20	Volts
Continuous Drain Current @ TC = 25°C	I _D	30	Amps
Operating and Storage Temperature	T _{op} & T _{stg}	-55 to +150	°C
Thermal Resistance, Junction to Case (All Four)	R _{θJC}	3.5	°C/W
Total Device Dissipation @ TC = 25°C	P _D	35	Watts

PACKAGE OUTLINE: 28 PIN CLCC

PIN OUT:

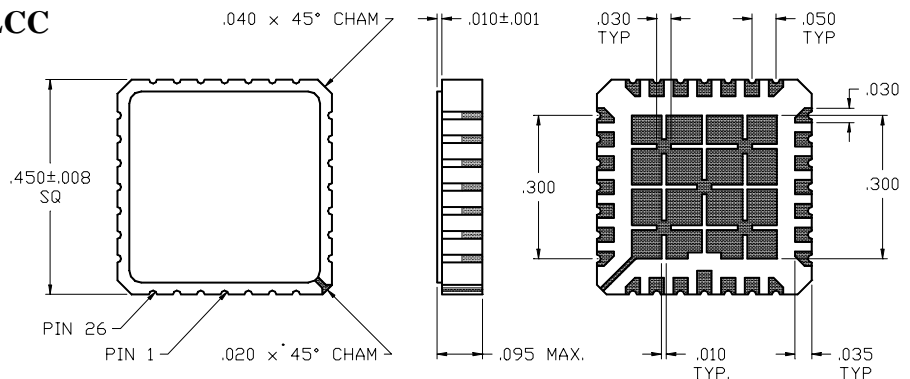
SOURCE: 1, 15 - 28

DRAIN: 5 - 11

GATE: 2, 3, 13, 14

NOTE:

All drain/source pins must be connected on the PC board in order to maximize current carrying capability and to minimize RDS (on)



NOTE: All specifications are subject to change without notification. SCD's for these devices should be reviewed by SSDI prior to release.

DATA SHEET #: FT0001A

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ELECTRICAL CHARACTERISTICS @ $T_J = 25^\circ\text{C}$ (Unless Otherwise Specified)

RATING	SYMBOL	MIN	TYP	MAX	UNIT
Drain to Source Breakdown Voltage ($V_{GS} = 0\text{ V}$, $I_D = 250\mu\text{A}$)	BV_{DSS}	60	-	-	V
Drain to Source ON State Resistance^{2/} ($V_{GS} = 10\text{ V}$)	$R_{DS(on)}$	60% of Rated I_D , $T_C = 25^\circ\text{C}$ Rated I_D , $T_C = 25^\circ\text{C}$ 60% of Rated I_D , $T_C = 150^\circ\text{C}$	- 23 25 27	25 27 -	$\text{m}\Omega$
Gate Threshold Voltage ($V_{DS} = V_{GS}$, $I_D = 250\mu\text{A}$)	$V_{GS(th)}$	2	-	4	V
Forward Transconductance ($V_{DS} > I_D(on) \times R_{DS(on)}$ Max, $I_{DS} = 60\%$ rated I_D)	g_{fs}	15	35	-	$\text{S}(\text{V})$
Zero Gate Voltage Drain Current ($V_{DS} = 80\%$ rated V_{DS} , $V_{GS} = 0\text{ V}$, $T_A = 25^\circ\text{C}$) ($V_{DS} = 80\%$ rated V_{DS} , $V_{GS} = 0\text{ V}$, $T_A = 125^\circ\text{C}$)	I_{DSS}	- -	- -	10 100	μA
Gate to Source Leakage Forward Gate to Source Leakage Reverse	At rated V_{GS}	I_{GSS}	- -	- -	100 100 nA
Total Gate Charge Gate to Source Charge Gate to Drain Charge	$V_{GS} = 10\text{ Volts}$ 50% rated V_{DS} Rated I_D	Q_g Q_{gs} Q_{gd}	- - -	83 13 40	100 20 55 nC
Turn on Delay Time Rise Time Turn off DELAY Time Fall Time	$V_{DD} = 50\%$ rated V_{DS} rated I_D $R_G = 6.2\ \Omega$	$t_{d(on)}$ t_r $t_{d(off)}$ t_f	- - - -	20 35 65 40	40 70 130 80 nsec
Diode Forward Voltage ($I_S = \text{rated } I_D$, $V_{GS} = 0\text{ V}$, $T_J = 25^\circ\text{C}$)	V_{SD}	-	1.47	1.6	V
Diode Reverse Recovery Time Reverse Recovery Charge	$T_J = 25^\circ\text{C}$ $I_F = 10\text{ A}$ $di/dt = 100\text{ A}/\mu\text{sec}$	t_{rr}	-	70	150 nsec
Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{GS} = 0\text{ Volts}$ $V_{DS} = 25\text{ Volts}$ $f = 1\text{ MHz}$	C_{iss} C_{oss} C_{rss}	- - -	2600 700 260	2900 1100 275 pF

For thermal derating curves and other characteristic curves please contact SSDI Marketing Department.

NOTES:

1/ Die Rating: 75Amps.

2/ All package pins of the same terminations (Drain/Source/Gate) must be connected together to minimize $R_{DS(on)}$ and maximize current carrying capability.